# Alexander Ermachikhin

List of Publications by Year
in descending order



| 42 | 77 | 1683354 5 | 1719596 7 |
|---|---|---|---|
| papers | citations | h-index | g-index |

| 42 | 42 | 42 | 69 |
|---|---|---|---|
| all docs | docs citations | times ranked | citing authors |

| # | Article | IF | Citations |
|---|---|---|---|
| 1 | A Setup for Measuring the Spectral Dispersion of External Quantum Efficiency. Instruments and Experimental Techniques, 2022, 65, 123-127. | 0.1 | 0 |
| 2 | Temperature activated conductivity of Ge<sub>2</sub>Sb<sub>2</sub>Te<sub>5</sub>: connection to the variation of Fermi level and implications on resistance drift. Journal Physics D: Applied Physics, 2021, 54, 315302. | 1.3 | 6 |
| 3 | Investigation of the properties of zinc oxide based heterostructures. Physics of Complex Systems, 2021, 2, 172-179. | 0.2 | 0 |
| 4 | Investigation of HIT solar cells low frequency noise characteristics. Journal of Physics: Conference Series, 2021, 2103, 012105. | 0.3 | 0 |
| 5 | Influence of deep level defects on photoelectrical processes in p-n junction solar cells with porous silicon antireflection coating. , 2020, , . | | 1 |
| 6 | Investigation of recombination centers in the active layers of HIT solar cells. , 2020, , . | | 0 |
| 7 | External Quantum Efficiency of Bifacial HIT Solar Cells. Semiconductors, 2020, 54, 1254-1259. | 0.2 | 3 |
| 8 | Structural Dependent Eu3+ Luminescence, Photoelectric and Hysteresis Effects in Porous Strontium Titanate. Materials, 2020, 13, 5767. | 1.3 | 8 |
| 9 | Kinetics of volume and surface driven crystallization in thin films. Journal of Physics Condensed Matter, 2020, 32, 355401. | 0.7 | 3 |
| 10 | Deep-Level Defects in a Photovoltaic Converter with an Antireflection Porous Silicon Film Formed by Chemical Stain Etching. Technical Physics Letters, 2019, 45, 145-148. | 0.2 | 1 |
| 11 | Current Transmission Mechanisms in the Semiconductor Structure of a Photoelectric Transducer with an n+â€“p Junction and an Antireflection Porous Silicon Film Formed by Color Etching. Technical Physics, 2019, 64, 686-692. | 0.2 | 0 |
| 12 | RESEARCH OF CHARGE TRANSFER MECHANISMS IN METAL-ZnO-SILICON HETEROSTRUCTURES. Vestnik of Ryazan State Radio Engineering University, 2019, 70, 179-189. | 0.0 | 1 |
| 13 | Mechanisms of Current Flow in the Diode Structure with an n + â€“p-Junction Formed by Thermal Diffusion of Phosphorus From Porous Silicon Film. Russian Physics Journal, 2018, 60, 1565-1571. | 0.2 | 2 |
| 14 | Application of Adaptive Algorithms for Measuring Temperature Current-Voltage Characteristics of Electronic Elements. , 2018, , . | | 0 |
| 15 | Measurement complex on the basis of AFM for investigating charge carrier distribution in semiconductor barrier structures. , 2018, , . | | 0 |
| 16 | Investigating and modeling high frequency C-V characteristics of zinc oxide-based heterostructures. , 2018, , . | | 0 |
| 17 | Spatial localization of dominating deep centers in multicrystalline silicon solar cells. , 2018, , . | | 0 |
| 18 | Measurement complex of photoluminescence using LabVIEW. , 2018, , . | | 0 |

| # | Article | IF | Citations |
|---|---|---|---|
| 19 | An Automated Measuring System for Current Deep-Level Transient Spectroscopy. Instruments and Experimental Techniques, 2018, 61, 277-282. | 0.1 | 4 |
| 20 | Excess noise and deep level defects diagnostics in semiconductor barrier structures. , 2018, , . | | 0 |
| 21 | Investigation of Au/ZnO/Si MIS structures by capacitance-voltage characteristics method. , 2018, , . | | 0 |
| 22 | Study of Current Flow Mechanisms in a CdS/por-Si/p-Si Heterostructure. Semiconductors, 2018, 52, 891-896. | 0.2 | 0 |
| 23 | Study of Deep Levels in a HIT Solar Cell. Semiconductors, 2018, 52, 926-930. | 0.2 | 3 |
| 24 | Investigation of electophysical characteristics of organic solar cells based on P3HT:PEDOT blend. , 2017, , . | | 0 |
| 25 | Investigation of recombination processes in multicrystalline silicon solar cells. , 2017, , . | | 1 |
| 26 | Local investigation of capacitance-voltage characteristics of silicon solar cell with the modified surface. , 2017, , . | | 1 |
| 27 | Investigation of (Ge<inf>2</inf>Sb<inf>2</inf>Te<inf>5</inf>)<inf>1â^'x</inf>Bi<inf>x</inf> thin films by low frequency noise spectroscopy. , 2017, , . | | 0 |
| 28 | Investigation of band diagram features of the DUWELL-structure InAs/InGaAs/GaAs by DLTS and low-frequency noise spectroscopy. , 2017, , . | | 0 |
| 29 | Investigation and simulation of voltage-noise characteristics of semiconductor barrier structures. , 2017, , . | | 1 |
| 30 | Measurement complex to investigate electrophysical and noise characteristics of semiconductor micro- and nanostructures. , 2017, , . | | 2 |
| 31 | An analytical solution for the Fermi level of the non-degenerate semiconductor in thermal equilibrium over a wide temperature range. , 2017, , . | | 1 |
| 32 | Defects with deep levels in a semiconductor structure of a photoelectric converter of solar energy with an antireflection film of porous silicon. Technical Physics Letters, 2017, 43, 955-957. | 0.2 | 3 |
| 33 | Investigation of Deep-Level Defects Lateral Distribution in Active Layers of Multicrystalline Silicon Solar Cells. MRS Advances, 2017, 2, 3141-3146. | 0.5 | 1 |
| 34 | An investigation of current-flow mechanisms in thin rubrene wafers prepared by the vapor transport method. Technical Physics Letters, 2016, 42, 1107-1109. | 0.2 | 0 |
| 35 | Specific features of current flow mechanisms in the semiconductor structure of a photoelectric converter with an n +â€“p-junction and an antireflective porous silicon film. Technical Physics, 2016, 61, 1694-1697. | 0.2 | 4 |
| 36 | Investigation of the Influence of Deep-Level Defects on the Conversion Efficiency of Sibased Solar Cells. MRS Advances, 2016, 1, 911-916. | 0.5 | 5 |

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|---|---|---|---|
| 37 | Low-resistance and high-resistance states in strontium titanate films formed by the solâ€“gel method. Physics of the Solid State, 2015, 57, 2030-2033. | 0.2 | 3 |
| 38 | The measuring systems of semiconductor structures and its software. , 2015, , . | | 8 |
| 39 | Complex Method of Diagnostics of Diode-Like Quantum Well Heterostructures with Use of Low Frequency Noise Spectroscopy. Journal of Nanoelectronics and Optoelectronics, 2015, 9, 756-761. | 0.1 | 6 |
| 40 | Apparatus for determining parameters of semiconductor structures by magnetic quantum effects and admittance spectroscopy. Instruments and Experimental Techniques, 2014, 57, 479-487. | 0.1 | 1 |
| 41 | Analysis of the electrostatic interaction of charges in multiple InGaAs/GaAs quantum wells by admittance-spectroscopy methods. Semiconductors, 2014, 48, 917-923. | 0.2 | 6 |
| 42 | A measuring System for the Spectroscopy of the Low-Frequency Noise of Semiconductor Diode Structures. Measurement Techniques, 2013, 56, 1066-1071. | 0.2 | 2 |